

Search Notes**Application/Control No.**

09/674,090

Examiner

Young J. Kim

Applicant(s)/Patent under Reexamination

EICHEN ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner
435	6	7/6/2005	YJK
	91.1	7/6/2005	YJK
	91.2	7/6/2005	YJK
536	24.3	7/6/2005	YJK
	24.33	7/6/2005	YJK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Databases (USPT, USPPG, EPO, JPO, DERWENT, IBM-TDB)	7/9/2005	YJK
See enclosed for search strategy	7/6/2005	YJK
NPL:search terms: electrodes, conductive bridge, bridge, nanowire, device	7/6/2005	YJK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner